Reject Ho Fail to reject The significance Type 2 error:  $P(Reject + 16) H_0 is true) = 0$ decision Rule O = 00 in H0. level Prob. of

Type II error: P (Fail to reject | H, is true) = B The Power of the test: the under the Ho: U= U. H (: U>llo) Decision Rule: Reject Ho If  $\bar{\chi} > C$ Best rejection region of level a.  $H_0: O = Q_0$   $V \cdot S. H_1: O = O_1$ def 4.4.1 simple hymeterses Best  $P(C|H_1) > P(D|H_1)$ "largect power" is chosen by comparing L(Oo) The points in the "best" critical region are selected by finding the smallest value of  $\frac{L(\vec{\chi} \mid \theta_0)}{L(\vec{\chi} \mid \theta_1)}$  $C = \frac{2}{3} \times \frac{1}{\sqrt{200}}$  has as small values as possible of 1 Neymann - Pearcon Leanna  $\frac{L(\vec{x}|\theta_0)}{L(\vec{x}|\theta_1)} \leq K \qquad \text{for} \qquad \vec{x} \in C$  $(ii) \quad P(\vec{X} \in C \mid Q_o) = Q \quad \Phi$ > The critical value c\* for Test statistic △ Some Extension. Ho: 0 = 0 v.s.  $H_1: 0 > 0$  of composite modify the method as. test statistic (known distribution)  $\frac{L(\vec{\chi} \mid \theta_0)}{L(\vec{\chi} \mid \theta_1)} < K \iff \text{transform}$   $L(\vec{\chi} \mid \theta_1)$   $\text{Value for } T(\vec{\chi})$ Where O, > Oo is a value in the alternative hypothesis.  $P(XCCH_o) = X$ In this case, the critical region C is called the" uniformly most powerful" critical region of level or. Not every test has the uniformly most powerful critical region of level or. Ho:  $Q = Q_0$  v.s.  $H_1: Q \neq Q_0$ Section 1: Some examples (i) Tesing on Il with known T<sup>2</sup> (normal population) Test-statistic:  $\overline{\chi} \sim \mathcal{N}(u, \frac{\nabla^2}{n})$ or  $Z = \frac{\overline{X} - \mathcal{U}}{\sqrt{n}} \sim \mathcal{N}(0,1)$  — Z - testone-sided test or two-sided test depends on H,.  $H_1: \mathcal{U} > \mathcal{U}_0$ ,  $Z > Z_{\alpha}$  P(Z > Z)H1: U<10, Z<-20 P(Z<Z) < 0  $H_1: \mathcal{M} \neq \mathcal{U}_0, \qquad |Z| > Z_{25} \qquad P(|Z| > Z)$ p-values < or critical values method. 2) Testing 11 with unknown 72 (normal population) Test statistic:  $X \sim N(U, T^2)$  $\frac{Z}{\sqrt{V/dt}} = T = \frac{X - U}{S/In} \sim t \cdot (n-1) \qquad ---- test$  $\frac{\overline{X} - \mathcal{U}}{\sqrt{\sqrt{n}}} = \frac{\overline{X} - \mathcal{U}}{\sqrt{\sqrt{n}}} \cdot \frac{\overline{X}}{\sqrt{n}} \cdot \frac{\overline{X}}{$  $5^{2} = \frac{\int_{n-1}^{n} \sum_{i=1}^{n} (x_{i} - \overline{x})^{2}}{(x_{i} - \overline{x})^{2}}, \frac{(n-1)S^{2}}{\sqrt{12}} \sim \chi^{2}(n-1)$ Testing M with known T2 Use alt to approximate the distribution of X in  $X(u, \frac{T^2}{n})$ Testing 72 (normal population)  $\zeta^2 = \frac{1}{N-1} \sum_{i=1}^{N} (X_i - \overline{X})^2, \qquad \frac{(N-1)\zeta^2}{N-2} \sim \chi^2(N-1) - \chi^2 + \text{test}$ Section 2: Binomial Data Binom (n, p) Ho: P=Po V-s. H.: P>Po A random sample of X,,..., Xn from a Bernoulli distribution with P. Ly A large sample test  $= \frac{1}{N} \sum_{n=1}^{N} X_n \cdot \frac{1}{N} \left( \frac{1}{N} , \frac{p(1-p)}{n} \right)$  $0 < np_0 - 3\sqrt{np_0(1-p_0)} < np_0 + 3\sqrt{np_0(1-p_0)} < n$   $Z = \frac{\overline{X-p_0}}{\sqrt{p_0(1-p_0)}} \sim N(0,1) \qquad Z - test$ Los A small sample test  $\longrightarrow X = \sum_{i \ge 1} X_i \sim \text{binom}(n, p)$ Section 3: 07, 16, 1-13. Type 2:

P (Reject Ho (Ho)) B= P(Fail forejett) H1) - as a function of o

1-B= P(Reject Ho) H1) - as a function of O.

MS Week12